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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO	CONFIRMATION NO	
10/690,835	10/21/2003	Subbareddy Kunegasabapethy	52069	5411	
21874 7596 96/03/2004			EXAM	EXAMINER	
EDWARDS & ANGELL, LLP			LEE, SIN J		
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BOSTON, MA	02205		ART UNIT	PAPER NUMBER	
			1752		

DATE MAILED: 06/03/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

			0,835	KANAGASABAPATHY ET AL.					
Office Action Summary		Exami	iner	Art Unit					
		Sin J.	Loe	1752					
The MAILING DATE of this communication appears on the cover sheet with the correspondence address – Period for Reply									
THE - Extended after aft	ORTENED STATUTORY PERIOD F MAILING DATE OF THIS COMMUN issues of time may be relatible under the provisions SIX (8) MONTHS from the milling date of this come pend for reply specified above, the maximum at 20 period for reply is specified above, the maximum at use to reply within the set or extended period for reply reply received by the Office later than three merities ded patient term adjustment 18-es 37 CFR 1-704(b).	ICATION. s of 37 CFR 1.136(e). In n munication. 30) days, a reply within the faultry penod will apply o y will, by statute, cause the	to event, however, may a reply! a statutory minimum of thirty (30 and will expire SIX (8) MONTHS a spolication to become ABAND	be tirrely filed) days will be considered tim from the meiling date of this ONED (35 U.S.C. § 133).	ety. communication.				
Status									
1)[X]	Responsive to communication(s) file	ed on 21 October	2003.						
-,-		2b)⊠ This action							
	Since this application is in condition			prosecution as to the	ne merits is				
-,-	closed in accordence with the prect								
Disposit	tion of Claims								
4100	Claim(s) 1-20 is/are pending in the	application.							
-,,	4a) Of the ebove claim(s) is/are withdrawn from consideration.								
5)[7]	Claim(s) Is/are allowed.								
	6)⊠ Claim(s) <u>1-9.11-14 and 17-20</u> is/are rejected.								
	7)⊠ Cleim(s) 10,15 and 16 is/are objected to.								
	Claim(s) are subject to restri		on requirement.						
Applicat	tion Papers								
91	The specification is objected to by the	e Examiner.							
10)	The drawing(s) filed on is/are	: a) accepted o	r b) objected to by	the Examiner.					
	Applicant may not request that any obje								
	Replacement drawing sheet(s) including	g the correction is re	quired if the drawing(s) i	s objected to. See 37	CFR 1.121(d).				
11)	The oath or declaration is objected t	to by the Examiner	. Note the attached O	ffice Action or form I	PTO-152.				
Priority	under 35 U.S.C. § 119								
12)	Acknowledgment is made of a claim	for foreign priority	under 35 U.S.C. § 11	9(a)-(d) or (f).					
a	☐ All b)☐ Some * c)☐ None of:								
	1. Certified copies of the priority	documents have	been received.						
	2. Certified copies of the priority	documents have	been received in Appl	ication No					
	3. Copies of the certified copies	of the priority doc	uments have been red	eived in this Nation	al Stege				
	application from the Internation	onal Bureau (PCT	Rule 17.2(a)).						
•	See the attached detailed Office active	on for a list of the o	certified copies not rec	elved.					
Attachme	nt/s)								
	ice of References Cited (PTO-892)		4) Interview Sum						
2) Noti	ice of Draftsperson's Patent Drawing Review (Paper No(s)/M	all Date nal Patent Application (P	TO 4500				
3) 🖾 Info	rmation Disclosure Statement(s) (PTO-1449 o er No(s)/Mail Date <u>03262004</u> .	r PTO/SB/08)	6) Other:	nai Palent Application (P	10-102)				

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DETAILED ACTION

Claim Rejections - 35 USC § 102

 The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A nerson shall be entitled to a patent unless --

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United chates.

 Claims 1, 9, 13, 14, and 20 are rejected under 35 U.S.C. 102(b) as being anticipated by Kawabe et al (JP 11-327145, its DERWENT English abstract, and its machine-assisted English translation provided by Japan Patent Office).

Kawabe teaches a positive photosensitive resin composition containing a polymer having an acid-decomposable group, an acid-generating compound, a compound having a sulfonamide structure, and one or more of fluorine and silicon type surfactants. See DERWENT abstract. Kawabe teaches (see [0051] of the machine English translation) a polysifoxane polymer as an example of the silicon type surfactant. Therefore, the prior art teaches present inventions of claims 1, 9, and 14.

In [0070]-[0071] of the machine English translation, Kawabe teaches the polymer made of norbomene, maleic anhydride, t-butyl acrylate, and acrylic acid monomer units as his polymer having an acid-decomposable group. Therefore, the prior art teaches present invention of claim 13.

With respect to present claim 20, in [0061] of the machine English translation, Kawabe teaches applying his photosensitive composition onto a substrate. Therefore, the prior art teaches present invention of claim 20. Claims 1-4, 6, 7, 14, 17, 19, and 20 are rejected under 35 U.S.C. 102(b) as being anticipated by Kawamura et al (EP 0 814 381 A1).

Kawamura teaches (see abstract) a positive image forming composition comprising an acid generating compound and a polymer having –SO₂-NR₃-CO- (a sulfonamide group) in which R₃ represents a tertiary allyl group, an alkoxymethyl group, an arylmethyl group or an alloyclic alkyl group. As one of the example for the polymer, Kawamura teaches (see po.23, lines 5-10, po.26, lines 14-21) the following polymer:

This polymer contains a silicon atom, a sulfonamide group, and a tert-butyl group (an acid labile group). Therefore, the prior art teaches present inventions of claims 1-4, 6, 7, and 14.

With respect to present claims 17, 19, and 20, Kawamura teaches (pg.33, line 56-58) papers laminated with polyethylene, polypropylene, or polystyrene as one of the examples for the support material to which his photosensitive composition is applied. After his photosensitive composition is coated onto a support, the photosensitive layer is exposed to a light source and then developed (see pg.34, lines 19-20, line 44-46, lines 55-58, pg.35, lines 1-6). Therefore, the prior art teaches present inventions of claims 17, 19, and 20.

 Claims 1-5, 8, 14, 17, 19, and 20 are rejected under 35 U.S.C. 102(b) as being anticipated by Mizutani (JP 2001-201855, its DERWENT English abstract, and its machine-assisted English translation provided by Japan Patent Office).

Mizutani teaches (see DERWENT abstract and claim 1 of the machine English translation) a composition comprising an acid-generating compound and a acid-decomposable resin which has a repeat unit selected from the following formulae (C1) and (C2):

$$R_{cr}$$
 R_{cr} R_{cr}

As examples for the repeat unit of the formula (C1) and (C2), Mizutani includes the following repeat units (see [0079]-[0083]);

Therefore, Mizutani teaches present inventions of claims 1-5 and 8.

With respect to present claims 17, 19, and 20, Mizutani teaches (see [0111] and [0113]) that after his photoresist composition is applied on a substrate, the resist film is exposed and then developed to obtain a resist pattern. Mizutani furthermore teaches that a lower layer of organic polymer membrane can be used under the upper resist

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layer made of his inventive composition to form a two-layer resist. Therefore, the prior art teaches present inventions of claims 17, 19, and 20.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all
obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title. If the differences between the subject matter sought to be patented and the prior at rea such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter portains. Patentability shall not be negative by the manner in which the invention was made.

 Claims 17-19 are rejected under 35 U.S.C. 103(a) as being unpatentable over (JP 11-327145, its DERWENT English abstract, and its machine-assisted English translation provided by Janan Patent Office) in view of Park et al (5.759,755).

As discussed above in Paragraph 2, Kawabe teaches applying his photosenative composition onto a substrate (Kawabe also teaches exposing the resist film and developing the exposed resist film in [0063], [0064], [0076]). Furthermore, Kawabe teaches (see [0061] of the machine English translation) that an antireflection film layer may exist if needed further on the substrate, but without giving details as to what kind of material can be used for the antireflection film layer. Park et al teaches making an anti-reflective layer (to be used in manufacturing a semiconductor device) made of phenol-based resin in order to eliminate the complexity of using conventional anti-reflective coating composition and reduce the production cost (see col. 1, lines 12-16, col.2, lines 34-43). Since Kawabe's composition is also used in making semiconduct or device (see [0001] of the English translation), and since Kawabe teaches that an antireflective film layer can further be formed on his substrate, it would have been obvious to one of

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ordinary skill in the art to form Park's anti-reflective layer made of phenoi-based resin on Kawabe's substrate in order to eliminate the complexity of using conventional antireflective coating composition and reduce the production cost. Therefore, Kawabe in view of Park would render obvious present inventions of claims 17-19.

 Claims 11 and 12 are rejected under 35 U.S.C. 103(a) as being unpatentable over Mizutani (JP 2001-201855, its DERWENT English abstract, and its machineassisted English translation provided by Japan Patent Office).

Mizutani is discussed in Paragraph 4 above.

With respect to present claims 11 and 12, the following repeating units (which were discussed above in Paragraph 4)

all meet the Mizutani's generic formulae (C1) and (C2). For those three repeating units shown above, R_{c1} and R_{c2} of the generic formula (C1) and (C2) are hydrogen atoms. Mizutani teaches the equivalence of the hydrogen atoms and carboxyl groups for those variables R_{c1} and R_{c2} (see DERWENT abstract). Therefore, because the prior art teaches the equivalence of the hydrogen atom and the carboxyl group for those variables R_{c1} and R_{c5} , it would have been obvious to one of ordinary skill in the art to replace H atoms in those positions R_{c1} and R_{c5} with carboxyl groups with a reasonable expectation of obtaining a positive photoresist composition having high sensitivity and

high resolving power in the production of a semiconductor device. Therefore, Mizutani's teaching would render obvious present inventions of claims 11 and 12.

Allowable Subject Matter

 Claims 10, 15, and 16 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

None of the cited prior arts teaches or suggests the present polymer that contains one or more Si atoms and a distinct polymer that comprises one or more sulfonamide groups as presently claimed in claim 10. None of the cited prior arts teaches or suggests neither the present crosslinker component of claim 15 nor the present reastly each to the component of claim 15 nor the present reastly each to the component of claim 15.

 Any inquiry concerning this communication or earlier communications from the examiner should be directed to Sin J. Lee whose telephone number is 571-272-1333.
 The examiner can normally be reached on Monday-Friday from 9:00 am EST to 5:30 pm EST.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Mark F. Huff, can be reached on 571-272-1385. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic

Business Center (EBC) at 866-217-9197 (toll-free).

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May 28, 2004

Sin J. Lee

Sin J. Lee Palent Examiner Technology Center 170